

Notice of References Cited	Application/Control No. 10/751,172	Applicant(s)/Patent Under Reexamination HAN, JAE-WON	
	Examiner Ha T. Nguyen	Art Unit 2812	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,725,119 B1	04-2004	Wake, Tomoko	700/121
	B	US-6,022,805 A	02-2000	Sumi, Hirofumi	438/677
	C	US-6,458,711 B1	10-2002	O'Brien et al.	438/745
	D	US-6,337,272 B1	01-2002	Hamanaka, Nobuaki	438/651
	E	US-5,275,963 A	01-1994	Cederbaum et al.	438/624
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

16m 6-24-5